DEPENDENCE OF REFRACTIVE INDEX ON THICKNESS OF ANTHRACENE CRYSTALLINE THIN FILMS

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We consider the fringe pattern which appears in a Jamet interferometer when measuring the refractive index for thin films of an anthracene crystal by the Puccianti method. It is shown that, with taking into account the Fabry—Perot interference in thin crystals, the shift of interference fringes is not proportional to the refractive index, but is described by a more complicated function, whose structure is determined both by the refractive index of an infinite crystal and the thickness of the sample.